

## P-Channel Enhancement Mode Field Effect Transistor



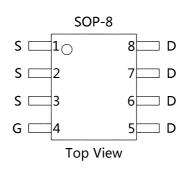
## **Product Summary**

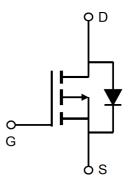
- VDS= -30V
- ID= -13A (VGS= -10V)
- $RDS(ON) \leq 10m \Omega @VGS = -10V$
- $RDS(ON) \leq 15.5m \Omega @VGS = -4.5V$

## Applications:

- **Notebook Computer**
- Portable Battery Pack







## **Absolute Maximum Ratings** (T<sub>A</sub> = 25 °C unless otherwise noted)

Symbol	Parameter	10s	Steady State	Units
V <sub>DS</sub>	Drain-Source Voltage	-30		V
V <sub>GS</sub>	Gate-Source Voltage	±20		V
I <sub>D</sub>	Continuous Drain Current <sup>1</sup>	-13	-9	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-50		Α
Is	Continuous Source Current (Diode Conduction) <sup>1</sup>	-2.7	-1.36	Α
PD	Maximum Power Dissipation <sup>1</sup>	3.0	1.5	W
TJ, Tstg	Operating Junction and Storage Temperature Range	-55 to 150		$^{\circ}$

## **Thermal Resistance Ratings**

Symbol	Parameter		Typical	Maximum	Unit	
R <sub>thJA</sub>	Maximum Junction-to-Ambient <sup>1</sup>	t≦10 Sec	33	42	°C/W	
		Steady State	70	82	C/VV	

### Notes:

- 1. Surface Mounted on 1" x 1" FR4 Board.
- 2. Pulse width limited by maximum junction temperature.

## **Features**

- Advanced Trench Process Technology.
- High Density Cell Design for Ultra Low On-Resistance.
- Lead free product is acquired.
- RoHS Compliant.

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# Electrical Characteristics (T<sub>A</sub>=25°C, unless otherwise noted)

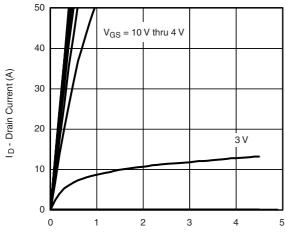
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
• Stati	c Characteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-30	-	-	٧
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = -250μA	-1.0	-1.5	-3.0	V
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V	-	-	-1	μΑ
I <sub>DSS</sub>		$V_{DS}$ = -24V, $V_{GS}$ = 0V, $T_J$ = 70 $^{\circ}$ C		-	-10	
Б	Drain Source On State Resistance <sup>a</sup>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -13A	-	8.5	10	mΩ
R <sub>DS(on)</sub>		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -10A	-	12.5	15.5	
<b>g</b> fs	Forward Transconductance <sup>a</sup>	V <sub>DS</sub> = -15V, I <sub>D</sub> = -13A	-	40	-	S
V <sub>SD</sub>	Diode Forward Voltage <sup>a</sup>	I <sub>S</sub> = -2.7A, V <sub>GS</sub> = 0V	-	-0.74	-1.1	V
• Dyna	mic Characteristics <sup>b</sup>		1			
Ciss	Input Capacitance		-	3340.0	-	
Coss	Output Capacitance	$V_{DS} = -15V, V_{GS} = 0V, f = 1MHz$	-	577.0	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	426.0	-	
Qg	Total Gate Charge		-	37.0	-	
Qgs	Gate-Source Charge	V <sub>DS</sub> = -15V, V <sub>GS</sub> = -5V, I <sub>D</sub> = -13A	-	10.0	-	nC
Q <sub>gd</sub>	Gate-Drain Charge		-	11.0	-	
t <sub>d(on)</sub>	Turn-On Delay Time		-	19.5	-	
tr	Rise Time	$V_{DD} = -15V, R_L = 15\Omega$	-	10.0	-	
T <sub>d(off)</sub>	Turn-Off Delay Time	$I_D = -1A$ , $V_{GEN} = -10V$ , $R_G = 6\Omega$	-	137.5	-	nSec
t <sub>f</sub>	Fall Time		-	55.3	-	
Rg	Gate Resistance	V <sub>GS</sub> = 0, V <sub>DS</sub> = 0, f = 1MHz	-	3.4	-	Ω
t <sub>rr</sub>	Source-Drain Reverse Recovery Time	I <sub>F</sub> = -2.1A, di/dt = 100A/μs	-	60	100	nSec

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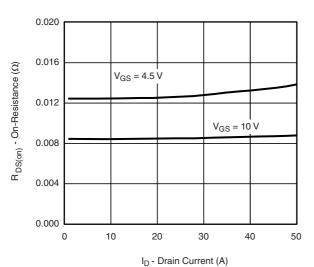
a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2%.

b. Guaranteed by design, not subject to production testing.

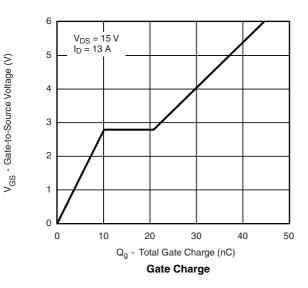
### Characteristics Curve (TA=25°C, unless otherwise noted)

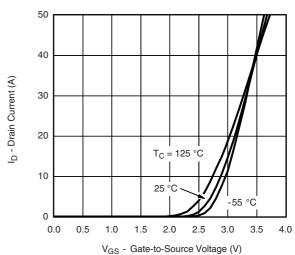




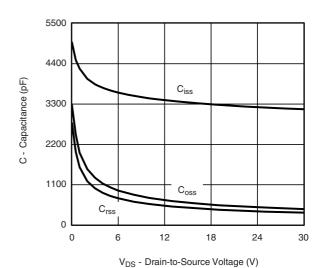


On-Resistance vs. Drain Current

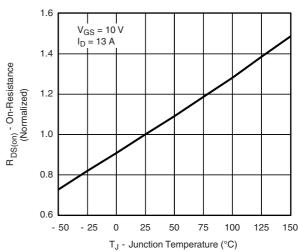




**Transfer Characteristics** 



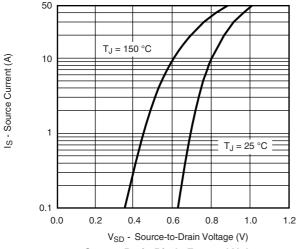
Capacitance



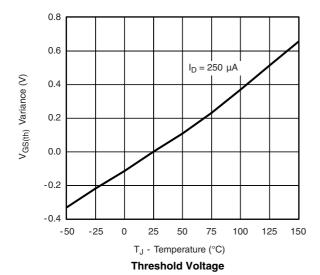
On-Resistance vs. Junction Temperature

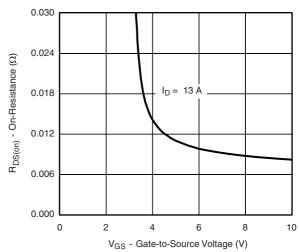
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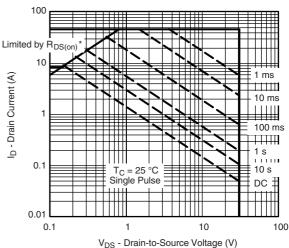


### Source-Drain Diode Forward Voltage

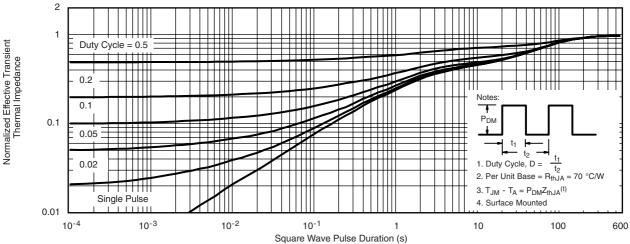




On-Resistance vs. Gate-to-Source Voltage



\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified Safe Operating Area, Junction-to-Case



Normalized Thermal Transient Impedance, Junction-to-Ambient

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